

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 219527US2S DIV		SERIAL NO. New Divisional Application	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT			
				FILING DATE Herewith		GROUP	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
<i>HN</i>	AA	5,687,160	11/97	Aotake et al.	—	—	
<i>HN</i>	AB	5,731,852	03/98	Lee	—	—	
<i>HN</i>	AC	6,185,365	02/01	Murase et al.	—	—	
<i>HN</i>	AD	6,067,400	05/00	Saeki et al.	—	—	
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION		
					YES	NO	
<i>HN</i>	AO	7-143429	06-02-95	JAPAN		X	
	AP						
	AQ						
	AR						
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AW						
	AX						
	AY						
	AZ					<input type="checkbox"/> Additional References sheet(s) attached	
Examiner <i>HUY NGUYEN</i>					Date Considered <i>4/18/03</i>		

11002 U.S. PTO
 10/076277
 02/19/02

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 219527US-2S DIV		SERIAL NO. 10/076,277	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Hideo ANDO et al.			
				FILING DATE February 19, 2002		GROUP 2615	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
<i>Hu</i>	AA	5,712,947	27 Jan 1998	Oguro et al.	—	—	
<i>Wu</i>	AB	6,148,138	14 Nov 2000	Sawabe et al.	—	—	
	AC						
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FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
<i>Hu</i>	AO	JP 5-158778	25 Jun 1993	Japan	x		
<i>Hu</i>	AP	JP 5-165935	2 July 1993	Japan	x		
<i>Wu</i>	AQ	JP 7-143429	2 Jun 1995	Japan (with Statement of Relevancy)			x
<i>Wu</i>	AR	JP 8-205014	9 Aug 1996	Japan	x		
<i>Wu</i>	AS	JP 9-182013	11 July 1997	Japan	x		
<i>Wu</i>	AT	JP 11-136613	21 May 1999	Japan	x		
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
<i>Wu</i>	AW	Explanation of Circumstances Concerning Accelerated Examination for Japanese Patent Application No. AD00201476 (with English Translation).					
<i>Wu</i>	AX	Explanation of Circumstances Concerning Accelerated Examination for Japanese Patent Application No. AD09804370 (with English Translation).					
<i>Wu</i>	AY	Explanation of Circumstances Concerning Accelerated Examination for Japanese Patent Application No. AD09904499 (with English Translation).					
	AZ						
Examiner <i>HUY NGUYEN</i>					Date Considered <i>4/18/03</i>		

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LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Hideo ANDO, et al			
				FILING DATE 02/19/02		GROUP 2615	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
<i>HN</i>	AA	6,385,389	7 May 2002	Maruyama et al.	—	—	
	AB						
	AC						
	AD						
	AE						
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FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
<i>HN</i>	AG	EP 1 065 665 A1	03 Jan 2001	EPO (In English)			
<i>HN</i>	AH	JP 5-81787	2 Apr 1993	JAPAN	X		
<i>HN</i>	AI	JP 8-106721	23 Apr 1996	JAPAN	X		
<i>HN</i>	AJ	JP 9-259539	3 Oct 1997	JAPAN	X		
<i>HN</i>	AK	JP 11-215471	6 Aug 1999	JAPAN			X
<i>HN</i>	AL	JP 11-238362	31 Aug 1999	JAPAN			X
	AM						
	AN						
	AO						
	AP						
	AQ						
	AR						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
<i>HN</i>	AS	Explanation of Circumstances Concerning Accelerated Examination for Japanese Patent Application No. 2001-310033 (with English Translation).					
<i>HN</i>	AT	Explanation of Circumstances Concerning Accelerated Examination for Japanese Patent Application No. 2001-310034 (with English Translation).					
<i>HN</i>	AU	Explanation of Circumstances Concerning Accelerated Examination for Japanese Patent Application No. 2001-310035 (with English Translation).					
<i>HN</i>	AV	Explanation of Circumstances Concerning Accelerated Examination for Japanese Patent Application No. 2001-310036 (with English Translation).					
<i>HN</i>	AW	Explanation of Circumstances Concerning Accelerated Examination for Japanese Patent Application No. 2001-310037 (with English Translation).					
	AX						
	AY						
	AZ						
Examiner <i>HUY NBU TEC</i>					Date Considered <i>4/18/03</i>		

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